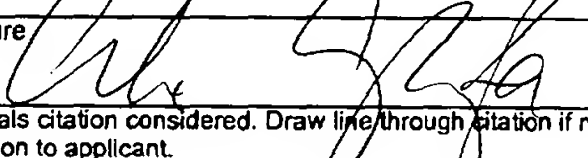


Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-038001	Application No. 09/852,672
	Applicant Hideomi Suzawa et al.		
	Filing Date May 11, 2001	Group Art Unit 2812	

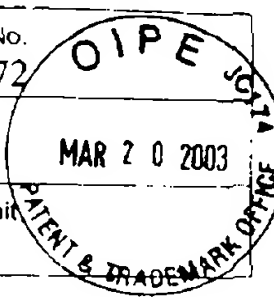
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-038001	Application No. 09/852,672
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hideomi Suzawa et al.	
		Filing Date May 11, 2001	Group Art Unit 2812



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